

<b>Notice of References Cited</b>		Application/Control No. 09/864,880	Applicant(s)/Patent Under Reexamination REEVE ET AL.	
		Examiner Van Kim T. Nguyen	Art Unit 2661	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,804,731	10-2004	Chang et al.	710/53
	B	US-6,757,246	06-2004	Alasti et al.	370/230
	C	US-6,747,971	06-2004	Hughes et al.	370/387
	D	US-6,707,824	03-2004	Achilles et al.	370/412
	E	US-6,654,343	11-2003	Brandis et al.	370/229
	F	US-6,625,160	09-2003	Suzuki, Hiroshi	370/413
	G	US-6,529,476	03-2003	Magnussen, Andreas	370/235
	H	US-6,542,507	04-2003	Khacherian et al.	370/395.43
	I	US-6,442,172	08-2002	Wallner et al.	370/416
	J	US-6,314,487	11-2001	Hahn et al.	710/317
	K	US-6,195,335	02-2001	Calvignac et al.	370/236
	L	US-5,982,771	11-1999	Caldara et al.	370/389
	M	US-5,463,620	10-1995	Sriram, Kotikalapudi	370/412

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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